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Type: Poster Presentation

Experimental longitudinal emittance manipulation using laser-based photoionization in the Fermilab Linac

Monday 11 August 2025 16:00 (2 hours)

A series of simulations and beam studies were conducted at Fermilab's linear accelerator to evaluate the effectiveness of longitudinal emittance control via laser-induced photoionization. While similar laser techniques have been employed at Fermilab to enhance injection and extraction efficiency into the Booster, the work presented here focuses on extending these methods to bunch-by-bunch manipulation. This approach utilizes fine-scale correction of the H⁻ bunches' longitudinal spatial distribution. In theory, loosely confined particles in longitudinal phase space contribute to emittance growth during acceleration. By selectively removing these outlying particles through laser scraping ($H^- + \gamma \rightarrow H + e^-$), this growth can be reduced. This report presents experimental results from both symmetric and asymmetric longitudinal scraping of H⁻ bunches in the Fermilab linac, which were subsequently injected into Booster, and evaluates the broader applicability of this method for future high-intensity accelerator operations.

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No

Would you like to submit this poster in student poster session on Sunday (August 10th)

Yes

Footnotes

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I have read and accept the Privacy Policy Statement

Yes

Author: LANDON, Parker (Boston University)

Co-authors: Dr RUAN, Jinhao (Fermi National Accelerator Laboratory); Prof. KEARNS, Edward (Boston University); Mr THOMPSON, Travente (Fermi National Accelerator Laboratory); JOHNSON, Dave (Fermi National Accelerator Laboratory); JOHNSON, Todd (Fermi National Accelerator Laboratory)

Presenter: LANDON, Parker (Boston University)

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